# X-ray diffraction experiments in quadrupolar Kondo candidate PrTi<sub>2</sub>Al<sub>20</sub> and PrV<sub>2</sub>Al<sub>20</sub>

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Crystal structure analyses in  $PrT_2Al_{20}$  (Tr = Ti and V) has been carried out. We found that Pr-Al cage for  $PrV_2Al_{20}$  is anisotropically deformed from sphere, which modify the crystalline-electric-field levels of  $Pr^{3+}$ . The information would provide a clue to understand the anomalous properties in  $PrT_2Al_{20}$ .

### 1 Introduction

Non-magnetic  $PrTr_2X_{20}$  (Tr = transition metal, X = Al and Zn) compounds have been extensively studied as candidates for the two channel (quadrupolar) Kondo effect. In PrV<sub>2</sub>Al<sub>20</sub>, magnetic susceptibility and electric resistivity show anomalous  $T^{1/2}$  behavior at low temperatures, which is in good accordance with the theoretical prediction for the two channel Anderson lattice model [1]. In stark contrast,  $PrTi_2Al_{20}$  shows  $T^2$ behavior below ~ 20 K. They show quite different ordering behavior. PrTi<sub>2</sub>Al<sub>20</sub> shows ferro-quadrupolar order at  $T \sim 2$  K [2]. In contrast,  $PrV_2Al_{20}$  shows successive non-magnetic anomalies at much lower temperatures around 0.6 K, of which the origin is suggested to be antiferro-quadrupolar type [3]. The crystal-electric-field (CEF) levels of Pr<sup>3+</sup> in PrTi<sub>2</sub>Al<sub>20</sub> were determined as  $\Gamma_3$  (quadrupolar- and octapolar-active ground state) -  $\Gamma_4$  (5.61) -  $\Gamma_5$  (9.30) -  $\Gamma_1$  (13.5 meV), whereas it was not explored in PrV<sub>2</sub>Al<sub>20</sub> [2]. The detailed knowledge on the crystal structures would provide a clue to understand the difference of the anomalous transport Thus, we reinvestigated crystal structure behavior. analysis of the  $PrTr_2Al_{20}$ .

## 2 Experiment

X-ray diffraction experiments were performed using single crystals with diameters of about 30  $\mu$ m on the BL-8A. The photon energy of the incident X-rays was tuned at 18 keV. X-ray beams were shaped into a square of 200 x 200  $\mu$ m<sup>2</sup> by a collimator. The intensity data were converted to the IFI-tables by using Rapid- Auto program, Rigaku. We used CrystalStructure program of Rigaku for analyzing the crystal structure from the IFI-table.

## 3 Results and Discussion

The crystal structure analyses for single crystals of  $PrTi_2Al_{20}$  and  $PrV_2Al_{20}$  were performed. The comparisons between observed and calculated structure factors are shown in Fig. 1(a). The crystal structure consists of two Al-cages with individually capturing Pr and *Tr* atoms as shown in Fig. 1(b). The CEF *x* and *W* parameters were known as x = 0.25(1) and W = -1.53(3)

K for  $PrTi_2AI_{20}$  [2]. Using the point charge calculation based on the refined structural parameters of Tr = Ti, we estimated the Al-charges that are consistent with the *x* and *W* parameters. The estimated Al-charges are +0.9 for Al(1) and +0.88 for Al(3). Next, we assumed that Alcharges estimated at Tr = Ti are also applied to Tr = V, and obtained  $x \sim 0.41$  and  $W \sim -2.1$  K using the point charge model based on the refined structural parameters for Tr = V. By these parameters, the CEF excited levels can be estimated as  $\Gamma_4 \sim 5.6$ ,  $\Gamma_5 \sim 11.1$ , and  $\Gamma_1 \sim 13.5$ meV for  $PrV_2AI_{20}$ . Detailed information is found in [4].

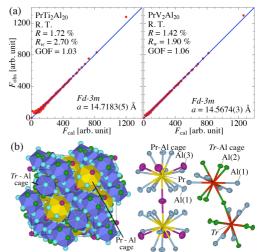


Fig. 1: (a) Observed  $(F_{obs})$  and calculated  $(F_{cal})$  structure factors for  $PrTr_2Al_{20}$  (Tr = Ti and V). (b) Schematic of crystal structure of  $PrTr_2Al_{20}$ .

#### References

[1] A. Sakai and S. Nakatsuji, J. Phys. Soc. Jpn. 80, 063701 (2011).

[2] T. J. Sato, S. Ibuka, Y. Nambu, T. Yamazaki, T. Hong, A. Sakai, and S. Nakatsuji, Phys. Rev. B **86**, 184419 (2012).

[3] Y. Nakanishi, M. Taniguchi, M. M. Nakamura, J. Hasegawa, R. Ohyama, M. Nakamura, M. Yoshizawa, M. Tsujimoto, S. Nakatsuji, Physica B **536** 125 (2018).

[4] D. Okuyama et al., J. Phys. Soc. Jpn. 88, 015001(2019). \*okudaisu@tohoku.ac.jp